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| <b>FORM PTO-1449/A and B (Modified)</b><br><br><b>INFORMATION DISCLOSURE<br/>STATEMENT BY APPLICANT</b> |   |    |   | APPLICATION NO.: Not Yet Assigned                |  | ATTY. DOCKET NO.: A0312.70522US00               |  |
|   |   |    |   | FILING DATE: <del>Here with</del> 2/25/04        |  | CONFIRMATION NO.: Not Yet Assigned              |  |
|   |   |    |   | APPLICANT: Richard P. Schubert                   |  |   |  |
|   |   |    |   | GROUP ART UNIT: <del>Not Yet Assigned</del> 2827 |  | EXAMINER: <del>Not Yet Assigned</del> David Lam |  |
| Sheet   | 1 | of | 1 |  |  |   |  |

## U.S. PATENT DOCUMENTS

| Examiner's<br>Initials | Cite<br>No. | U.S. Patent Document |              | Name of Patentee or Applicant of Cited<br>Document | Date of Publication or of issue<br>of Cited Document<br>MM-DD-YYYY |
|------------------------|-------------|----------------------|--------------|--|--|
|                        |             | Number               | Kind<br>Code |  |  |
| DL                     | A1          | 5,559,745            |              | Banik et al.                                       | 09/24/1996   |
| DL                     | A2          | 5,920,517            |              | Wendell  | 07/06/1999   |
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## FOREIGN PATENT DOCUMENTS

| Examiner's<br>Initials | Cite<br>No. | Foreign Patent Document |        |              | Name of Patentee or Applicant of Cited<br>Document<br>(not necessary) | Date of<br>Publication of<br>Cited Document<br>MM-DD-YYYY | Translation<br>(Y/N) |
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## OTHER ART — NON PATENT LITERATURE DOCUMENTS

| Examiner's<br>Initials | Cite<br>No | Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item<br>(book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s),<br>publisher, city and/or country where published. | Translation<br>(Y/N) |
|------------------------|------------|---|----------------------|
| DL                     | C1         | "Data Retention System", IBM Technical Disclosure Bulletin, May 1975, pp. 1-2;  |                      |
| DL                     | C2         | "Checking Random Access Memory", IBM Technical Disclosure Bulletin, March 1978, pp. 1-2;  |                      |
| DL                     | C3         | Ding-Ming Kwai et al., "Detection of SRAM Cell Stability by Lowering Array Supply Voltage", Proceedings of<br>the 9 <sup>th</sup> Asian Test Symposium, 2000 IEEE;  |                      |
| DL                     | C4         | Anne Meixner et al., "WEAK WRITE TEST MODE: An SRAM Cell Stability Design For Test", pp. 309-318,<br>IEEE 1996  |                      |

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| EXAMINER<br><i>DA Fu</i> | DATE CONSIDERED<br>11/05 |
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#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\*a copy of this reference is not provided as it was previously cited by or submitted to the office in a prior application, Serial No. \_\_, filed \_\_, and relied upon for an earlier filing date under 35 U.S.C. 120 (continuation, continuation-in-part, and divisional applications).